EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	16	test$3 near5 mixed signal semiconductor device$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:07
L2	40366	device interface	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:07
L3	17967	device under test	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:08
L7	25	control unit and (processor and operating system and computational modules)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:11
L8	118	device testing unit	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:11
L10	12	l1 and (l2 or l3 or l7 or l8)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:11

L15	1	executing second test same (((concurrently) or (parallel) or (simultaneouly) or (at the same time)) and (processing adj (test data) or (test result near2 first test)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:21
L16	5543	((concurrently) or (parallel) or (simultaneouly) or (at the same time)) and (first test same second test)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:24
L17	1	l10 and l16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:24
L18	15322	714/724,725,733,734,10,11,30,38,742,740,776;702/118;716/4.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:25
L19	400	l18 and (l10 or l16)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:25
L20	5	l18 and l10	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:26
L22	1	l20 and l16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2009/04/26 09:26

4/26/09 9:47:21 AM

C:\ Documents and Settings\ pchung\ My Documents\ EAST\ Workspaces\ 10614997.wsp